

US009543431B2

# (12) United States Patent Yu et al.

## (54) RADIO FREQUENCY LDMOS DEVICE AND

(71) Applicant: SHANGHAI HUAHONG GRACE

SEMICONDUCTOR MANUFACTURING

A FABRICATION METHOD THEREFOR

CORPORATION, Shanghai (CN)

(72) Inventors: Han Yu, Shanghai (CN); Zhengliang

Zhou, Shanghai (CN); Xi Chen,

Shanghai (CN)

(73) Assignee: Shanghai Huahong Grace

Semiconductor Manufacturing Corporation, Shanghai (CN)

(\*) Notice: Subject to any disclaimer, the term of this

patent is extended or adjusted under 35

U.S.C. 154(b) by 0 days.

(21) Appl. No.: 14/978,267

(22) Filed: Dec. 22, 2015

(65) Prior Publication Data

US 2016/0190310 A1 Jun. 30, 2016

(30) Foreign Application Priority Data

Dec. 29, 2014 (CN) ...... 2014 1 0842286

(51) Int. Cl.

**H01L 29/66** (2006.01) **H01L 29/78** (2006.01)

**H01L 29/10** (2006.01) **H01L 29/40** (2006.01)

H01L 23/66 (2006.01)

(52) U.S. Cl.

CPC ...... H01L 29/7816 (2013.01); H01L 23/66

(10) Patent No.: US 9,543,431 B2

(45) **Date of Patent: Jan. 10, 2017** 

(2013.01); *H01L 29/1095* (2013.01); *H01L* 29/402 (2013.01); *H01L 29/66681* (2013.01); *H01L 2924/0002* (2013.01)

(58) Field of Classification Search

CPC ...... H01L 29/7816; H01L 23/66; H01L 29/66681; H01L 29/402; H01L 29/1095

See application file for complete search history.

(56) References Cited

#### U.S. PATENT DOCUMENTS

2007/0090451 A1 4/2007 Lee

2008/0308862 A1\* 12/2008 Theeuwen ............ H01L 29/402 257/328

(Continued)

#### FOREIGN PATENT DOCUMENTS

CN 1828942 A 9/2006 CN 102237406 A 11/2011

Primary Examiner — Thanh Y Tran

(74) Attorney, Agent, or Firm — MKG, LLC

### (57) ABSTRACT

A radio frequency LDMOS device, wherein the drift region includes a first injection region and a second injection region; the first injection region situated between a second lateral surface of a polysilicon gate and a second lateral surface of a first Faraday shielding layer; the second injection region situated between the second lateral surface of the first Faraday shielding layer and the drain region and encloses the drain region; the second lateral surface of the second Faraday shielding layer is a surface of a side near the drain region, the maximum electric field strength of the drift region on the bottom of the second lateral surface of the second Faraday shielding layer is regulated via regulation of the doping concentration of the second injection region; the doping concentration of the first injection region is higher than the second injection region.

#### 14 Claims, 6 Drawing Sheets

